

# VQ2000 SERIES

**Siliconix**  
incorporated

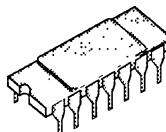
P-Channel Enhancement-Mode MOS Transistor  
Arrays

## PRODUCT SUMMARY

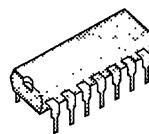
PART NUMBER	$V_{(BR)DSS}$ (V)	$r_{DS(ON)}$ ( $\Omega$ )	$I_D$ (A)	PACKAGE
VQ2000J	-60	10	-0.24	Plastic
VQ2000P	-60	10	-0.24	Side Braze

Performance Curves: VPDS06 (See Section 7)

14-PIN DIP  
SIDE BRAZE

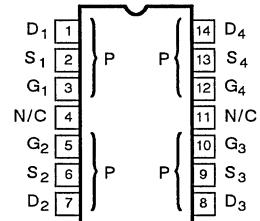


14-PIN PLASTIC



TOP VIEW

Dual-In-Line Package



## ABSOLUTE MAXIMUM RATINGS ( $T_A = 25^\circ\text{C}$ unless otherwise noted)

PARAMETERS/TEST CONDITIONS	SYMBOL	VQ2000J	VQ2000P	UNITS
Drain-Source Voltage	$V_{DS}$	-60	-60	V
Gate-Source Voltage	$V_{GS}$	$\pm 30$	$\pm 20$	
Continuous Drain Current	$I_D$	-0.24	-0.24	A
		-0.15	-0.15	
Pulsed Drain Current <sup>1</sup>	$I_{DM}$	$\pm 0.8$	$\pm 0.8$	W
Power Dissipation – Single	$P_D$	1.3	1.3	
		0.52	0.52	
Power Dissipation – Quad		2	2	
		0.8	0.8	
Operating Junction and Storage Temperature	$T_J, T_{stg}$	-55 to 150		°C
Lead Temperature (1/16" from case for 10 seconds)	$T_L$	300		

## THERMAL RESISTANCE

THERMAL RESISTANCE	SYMBOL	VQ2000J	VQ2000P	UNITS
Junction-to-Ambient – Single	$R_{thJA}$	96.2	96.2	°C/W
Junction-to-Ambient – Quad		62.5	62.5	

<sup>1</sup>Pulse width limited by maximum junction temperature

ELECTRICAL CHARACTERISTICS <sup>1</sup>			LIMITS			
PARAMETER	SYMBOL	TEST CONDITIONS	TYP <sup>2</sup>	VQ2000		UNIT
				MIN	MAX	
<b>STATIC</b>						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0 \text{ V}, I_D = -10 \mu\text{A}$	-70	-60		V
Gate Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS} = V_{GS}, I_D = -1 \text{ mA}$	-1.7	-1	-3	
Gate-Body Leakage	$I_{GSS}$	$V_{DS} = 0 \text{ V}$ $V_{GS} = \pm 20 \text{ V}$	$\pm 1$		$\pm 10$	$\text{nA}$
Zero Gate Voltage Drain Current	$I_{DSS}$	$V_{DS} = -48 \text{ V}$ $V_{GS} = 0 \text{ V}$	$\pm 5$		$\pm 50$	
On-State Drain Current <sup>3</sup>	$I_{D(\text{ON})}$	$T_J = 125^\circ\text{C}$	-0.02		-1	$\mu\text{A}$
On-State Drain Current <sup>3</sup>	$I_{D(\text{ON})}$	$T_J = 125^\circ\text{C}$	-0.2		-200	
Drain-Source On-Resistance <sup>3</sup>	$r_{DS(\text{ON})}$	$V_{GS} = -4.5 \text{ V}, I_D = -25 \text{ mA}$	15		25	$\Omega$
Forward Transconductance <sup>3</sup>	$g_{FS}$	$V_{GS} = -10 \text{ V}$ $I_D = -0.25 \text{ A}$	8		10	
Common Source Output Conductance <sup>3</sup>	$g_{os}$	$T_J = 125^\circ\text{C}$	15		20	
<b>DYNAMIC</b>						
Input Capacitance	$C_{iss}$	$V_{DS} = -25 \text{ V}$ $V_{GS} = 0 \text{ V}$ $f = 1 \text{ MHz}$	15		60	$\text{pF}$
Output Capacitance	$C_{oss}$		10		25	
Reverse Transfer Capacitance	$C_{rss}$		3		5	
<b>SWITCHING</b>						
Turn-On Time	$t_{d(\text{ON})}$	$V_{DD} = -25 \text{ V}, R_L = 133 \Omega$ $I_D = -0.18 \text{ A}, V_{GEN} = -10 \text{ V}$ $R_G = 25 \Omega$  (Switching time is essentially independent of operating temperature)	6		15	$\text{ns}$
	$t_r$		10		20	
Turn-Off Time	$t_{d(\text{OFF})}$		7		15	
	$t_f$		8		20	

NOTES: 1.  $T_A = 25^\circ\text{C}$  unless otherwise noted.

2. For design aid only, not subject to production testing.

3. Pulse test;  $PW = 300 \mu\text{s}$ , duty cycle  $\leq 2\%$ .